Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/808,330	TOIZUMI ET AL.
Examiner	Art Unit
Huan H. Tran	2861

SEARCHED				
Class	Subclass	Date	Examiner	
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			:	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	ice search see printout	2/8/2006	ННТ	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT; US_PGPUB;EPO;JPO;IBM-TDB)_see search history printout	2/8/2006	ннт
347/129,130,140; 399/136,168-221 (text search only_see search history printout)	2/8/2006	ннт